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億光電子工業股份有限公司 EVERLIGHT ELECTRONICS CO., LTD. 台北縣土城市中央路三段76巷25號



NO. 25, LANE 76, SEC. 3, CHUNG YANG ROAD, TUCHENG, TAIPEI, TAIWAN, R. O. C.

以下測試樣品係由客户送樣,且由客户聲稱並經客户確認如下 (The following samples was/were submitted and identified by/on behalf of the client as):

BASIC INFORMATION				
Type of Product	SMD C TYPE			
Supplier Company Name	EVERLIGHT			
Address	NO. 25, LANE 76, SEC. 3, CHUNG YANG ROAD, TUCHENG, TAIPEI, TAIWAIR. O. C.			
Tel/Fax/Email	TEL:886-2-267-2000 EXT:6315			
	FAX:886-2-267-9948			
	E-MAIL: hjyang@everlight.com			
Contact Person	HSIU JU YANG			
EVERLIGHT REPORT NO	EVERLIGHT-62-127A -SGS-11/03/2010			
PRODUCT INFORMATION				
Product/component Sample description	TFT BACKLIGHT			
Quantity (numbers or weight)	0.044g			
Supplier P/N	62-127A			
Product Lot No	Y10021291401			
Country of Origin	TAIWAN			
TEST INFORMATION				
Digital Photo(s) of sample(s) after being	JPG EMBEDDED IN EACH REPORT			
prepared				
Sample preparation	CUTTING			
Test Method	Cd , Pb , Hg , Cr(VI), PBB/PBDE - IEC 62321, Halogen-BS EN 14582			
PQL and/or MDL	Cd , Pb , Hg: < 2 mg/kg; PBB/PBDE: < 5 mg/kg; Halogen: 50 mg/kg			
Name of Analyzer	Cd , Pb , Hg, Cr(VI): Climbgreat Yang;			
	PBB/PBDE: Roman Wong; Halogen: Rita Chen			
收件日期(Sample Receiving Date) :	2010/03/05			

收件日期(Sample Receiving Date)

測試期間(Testing Period)

2010/03/05 TO 2010/03/11

請見下一頁 (Please refer to next pages).

Chenyu Kung / Operation Manager Signed for and on behalf of SGS TAIWAN LTD. Chemical Laboratory - Taipei

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測試結果(Test Results)

測試部位(PART NAME) NO.1 62-127A

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) NO.1
鎬 / Cadmium (Cd)	mg/kg	參考IEC 62321: 2008方法,以感應藕 合電漿原子發射光譜儀檢測. / With reference to IEC 62321: 2008 and performed by ICP-AES.	2	n.d.
鉛 / Lead (Pb)	mg/kg	參考IEC 62321: 2008方法, 以感應藕 合電漿原子發射光譜儀檢測. / With reference to IEC 62321: 2008 and performed by ICP-AES.	2	n.d.
汞 / Mercury (Hg)	mg/kg	參考IEC 62321: 2008方法, 以感應藕 合電漿原子發射光譜儀檢測. / With reference to IEC 62321: 2008 and performed by ICP-AES.	2	n.d.
六價鉻 / Hexavalent Chromium Cr(VI) by alkaline extraction	mg/kg	参考IEC 62321: 2008方法,以UV-VIS 檢測. / With reference to IEC 62321: 2008 and performed by UV- VIS.	2	n.d.
全氟辛烷磺酸 / Perfluorooctane sulfonates (PFOS) PFOS — Acid PFOS — Metal Salt PFOS — Amide	mg/kg	参考US EPA 3540C: 1996方法,以液相層析質譜儀檢測全氟辛烷磺酸含量./ With reference to US EPA 3540C: 1996 method for PFOS Content. Analysis was performed by LC/MS.	10	n.d.
全氟辛酸(銨) / PFOA (CAS No.: 000335-67-1)	mg/kg	參考US EPA 3540C: 1996方法,以液相層析質譜儀檢測全氟辛酸(銨)含量./ With reference to US EPA 3540C: 1996 method for PFOA Content. Analysis was performed by LC/MS.	10	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) NO.1
四溴雙酚-A / Tetrabromobisphenol A (TBBP-A) (CAS No.: 000079-94-7)	mg/kg	参考DIN 53313方法,以氣相層析儀/質 譜儀檢測. / With reference to DIN 53313. Analysis was performed by GC/MS.	10	n.d.
多溴聯苯總和 / Sum of PBBs			-	n.d.
一溴聯苯 / Monobromobiphenyl			5	n.d.
二溴聯苯 / Dibromobiphenyl			5	n.d.
三溴聯苯 / Tribromobiphenyl			5	n.d.
四溴聯苯 / Tetrabromobiphenyl			5	n.d.
五溴聯苯 / Pentabromobiphenyl			5	n.d.
六溴聯苯 / Hexabromobiphenyl		参考IEC 62321: 2008方法, 以氣相層 析儀/質譜儀檢測. / With reference	5	n.d.
七溴聯苯 / Heptabromobiphenyl			5	n.d.
八溴聯苯 / Octabromobiphenyl			5	n.d.
九溴聯苯 / Nonabromobiphenyl			5	n.d.
十溴聯苯 / Decabromobiphenyl	/1		5	n.d.
多溴聯苯醚總和 / Sum of PBDEs	mg/kg	to IEC 62321: 2008 and performed	-	n.d.
一溴聯苯醚 / Monobromodiphenyl ether		by GC/MS.	5	n.d.
二溴聯苯醚 / Dibromodiphenyl ether			5	n.d.
三溴聯苯醚 / Tribromodiphenyl ether			5	n.d.
四溴聯苯醚 / Tetrabromodiphenyl ether	1		5	n.d.
五溴聯苯醚 / Pentabromodiphenyl ether	1		5	n.d.
六溴聯苯醚 / Hexabromodiphenyl ether			5	n.d.
七溴聯苯醚 / Heptabromodiphenyl ether			5	n.d.
八溴聯苯醚 / Octabromodiphenyl ether			5	n.d.
九溴聯苯醚 / Nonabromodiphenyl ether]		5	n.d.
十溴聯苯醚 / Decabromodiphenyl ether			5	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) NO.1
多苯環芳香族化合物 / Polynuclear				
Aromatic Hydrocarbons (PAHs)				
Acenaphthene (CAS No.: 000083-32-9)			0.2	n.d.
Acenaphthylene (CAS No.: 000208-96-8)			0.2	n.d.
Anthracene (CAS No.: 000120-12-7)			0.2	n.d.
Benzo(a)anthracene (CAS No.: 000056-55-3)			0.2	n.d.
Benzo(a)pyrene (CAS No.: 000050-32-8)			0.2	n.d.
Benzo(b)fluoranthene (CAS No.: 000205-99-2)		参考ZLS standard ZEK 01.2-08方法,以氣相層析質譜儀(GC/MS)檢測./ With reference to ZLS standard ZEK 01.2-08 method. Analysis was performed by GC/MS.	0.2	n.d.
Benzo(g,h,i)perylene (CAS No.: 000191-24-2)	mg/kg		0.2	n.d.
Benzo(k)fluoranthene (CAS No.: 000207-08-9)			0.2	n.d.
Chrysene (CAS No.: 000218-01-9)			0.2	n.d.
Dibenzo(a,h)anthracene (CAS No.: 000053-70-3)			0.2	n.d.
Fluoranthene (CAS No.: 000206-44-0)			0.2	n.d.
Fluorene (CAS No.: 000086-73-7)	-		0.2	n.d.
Indeno[1,2,3-c,d] pyrene (CAS No.: 000193-39-5)			0.2	n.d.
Naphthalene (CAS No.: 000091-20-3)			0.2	n.d.
Phenanthrene (CAS No.: 000085-01-8)			0.2	n.d.
Pyrene (CAS No.: 000129-00-0)			0.2	n.d.
多苯環芳香族化合物16項總和 / Sum of 16 PAHs			-	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) NO.1
可塑劑定量分析 / Phthalates				
鄰苯二甲酸甲苯基丁酯 / BBP (Benzyl butyl phthalate) (CAS No.: 000085- 68-7)	%	參考EN 14372, 以氣相層析儀/質譜儀 檢測之. / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二 (2-乙基己基)酯 / DEHP (Di- (2-ethylhexyl) phthalate) (CAS No.: 000117-81-7)	%	參考EN 14372, 以氣相層析儀/質譜儀 檢測之. / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二異癸酯 / DIDP (Di- isodecyl phthalate) (CAS No.: 026761-40-0)	%	參考EN 14372, 以氣相層析儀/質譜儀 檢測之. / With reference to EN 14372. Analysis was performed by GC/MS.	0.01	n.d.
鄰苯二甲酸二異壬酯 / DINP (Di- isononyl phthalate) (CAS No.: 028553-12-0)	%	參考EN 14372, 以氣相層析儀/質譜儀 檢測之. / With reference to EN 14372. Analysis was performed by GC/MS.	0.01	n.d.
鄰苯二甲酸二正辛酯 / DNOP (Di-n- octyl phthalate) (CAS No.: 000117- 84-0)	%	參考EN 14372, 以氣相層析儀/質譜儀 檢測之. / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二丁酯 / DBP (Dibutyl phthalate) (CAS No.: 000084-74-2)	%	參考EN 14372, 以氣相層析儀/質譜儀 檢測之. / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鹵素 / Halogen				
鹵素(氟)/ Halogen-Fluorine (F) (CAS No.: 014762-94-8)	mg/kg	参考BS EN 14582:2007, 以離子層析儀 分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) NO.1
鹵素(氣)/ Halogen-Chlorine (C1) (CAS No.: 022537-15-1)	mg/kg	参考BS EN 14582:2007, 以離子層析儀 分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素(溴)/ Halogen-Bromine (Br) (CAS No.: 010097-32-2)	mg/kg	参考BS EN 14582:2007, 以離子層析儀 分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素(碘)/ Halogen-Iodine (I) (CAS No.: 014362-44-8)	mg/kg	多考BS EN 14582:2007, 以離子層析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.

備註(Note):

- 1. mg/kg = ppm ; 0.1wt% = 1000ppm
- 2. n.d. = Not Detected (未檢出)
- 3. MDL = Method Detection Limit (方法偵測極限值)
- 4. "-" = Not Regulated (無規格值)

PFOS参考資訊(Reference Information): 指令 2006/122/EC (Directive 2006/122/EC)

- (1) 該物質不可置於市場上或使用於特殊物質或配置成分重量濃度等於或大於0.005%.
 - (May not be placed on the market or used as a substance or constituent of preparations in a concentration equal to or higher than 0.005 % by mass.)
- (2) 該物質不可置於市場上的半成品或商品或其物件;假若零件上明顯地具有PFOS並參照結構上及微細構造上計算 PFOS重量濃度等於或大於0.1%, 而紡織品或其他覆蓋物質, 如果PFOS在覆蓋物質中含量等於或大於1μg/m². (May not be placed on the market in semi-finished products or articles, or parts thereof, if the concentration of PFOS is equal to or higher than 0.1 % by mass calculated with reference to the mass of structurally or microstructurally distinct parts that contain PFOS or, for textiles or other coated materials, if the amount of PFOS is equal to or higher than $l\mu g/m^2$ of the coated material.)

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<u> 參考資料(Reference information):</u>

依據ZEK 01.2-08之要求:產品中最大值為

(Requirement of ZEK 01.2-08: Restraining maximum values for products)

項目 (Parameter)	第1類 (Category 1)	第2類 (Category 2)	第3類 (Category 3)	
	與食品接觸或放入嘴内的	持續地(長時間)與皮膚接	暫時地(短時間)與皮膚接	
	材料,以及給三歲以下的	觸逾30秒,以及不屬第1	觸但不逾30秒或不會與	
	幼兒使用的玩具.	類的玩具.	皮膚接觸.	
	(Materials in contact	(Materials with	(Materials with	
	with foodstuff or	foreseeable skin	foreseeable skin	
	materials which are	contact >30 s	contact <30 s (short	
	meant to put in the		time skin contact) or	
	mouth as well as toys	contact) and toys not	without skin contact.)	
	for children <36	covered by category 1.)		
	months.)			
苯騈(a)芘				
Benzo(a)pyrene (mg/kg)	<mdl (<0.2)**<="" td=""><td>1</td><td>20</td></mdl>	1	20	
環保署規範16項PAH				
總濃度 (Sum of 16	<mdl (<0.2)**<="" td=""><td>10</td><td>200</td></mdl>	10	200	
EPA-PAH) (mg/kg)*				

注意(Remark): * = PAH濃度大於0.2mg/kg時,則須計算PAH總濃度值

(Only PAH substances >0.2 mg/kg are taken into account while calculating the sum of PAHs)

** = 最大濃度值超出等級一的限制,但在等級二的濃度限制值内時,可能需要確認測試材質 是否合適於食品容器或是依照DIN EN1186ff/ \$64 LFGB 80.30-1方法,針對特定PAH的 遷移測試進行測試。遷移測試的結論需依照食品法規規範

(In case that the maximum values exceed the limits of category 1, but are within the limits of category 2, one may confirm the suitability of the tested material for contact with foodstuff or oral mucosa by additional specific migration tests of PAH components based on DIN EN 1186ff and § 64 LFGB 80.30-1. The conclusion of the migration test results must be made based on food law criteria.)

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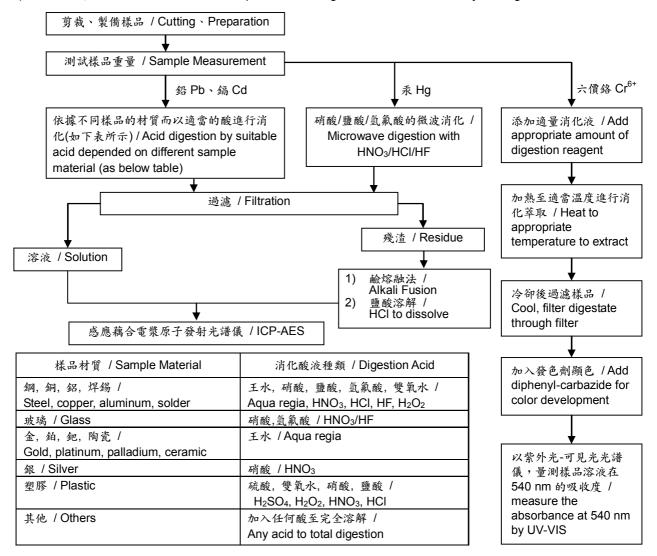
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- 1) 根據以下的流程圖之條件,樣品已完全溶解。(六價鉻測試方法除外) / These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr⁶⁺ test method excluded)
- 2) 測試人員:楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 3) 測試負責人: 張啓興 / Name of the person in charge of measurement: Troy Chang



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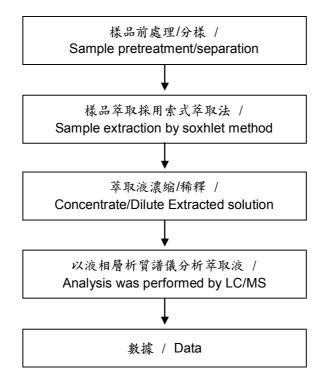
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索式萃取(LC/MS)分析流程圖 /

Analytical flow chart of Soxhlet extraction (LC/MS) procedure

- 1) 測試人員:傅莉雅 / Name of the person who made measurement: Lydia Fu
- 2) 測試負責人: 陳新智 / Name of the person in charge of measurement: Shinjyh Chen
- 測試項目(Test Items): 全氟辛烷磺酸/全氟辛酸(銨)、苯並三唑類化合物 / PFOS/PFOA、Benzotriazole



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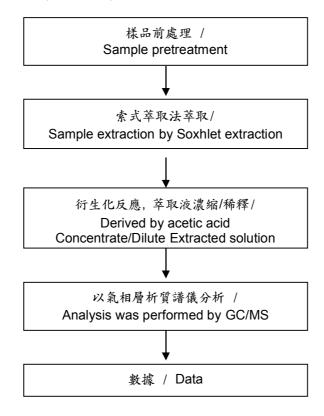
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分析流程圖 / analytical flow chart

- 1) 測試人員: 傳舒萱 / Name of the person who made measurement: Amanda Fu
- 2) 測試負責人: 陳新智 / Name of the person in charge of measurement: Shinjyh Chen
 - 測試項目(Test Items):四溴雙酚-A、雙酚 A/TBBP-A、Bisphenol A



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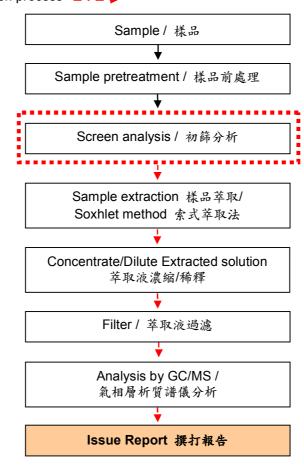
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NO. 25, LANE 76, SEC. 3, CHUNG YANG ROAD, TUCHENG, TAIPEI, TAIWAN, R. O. C.

多溴聯苯/多溴聯苯醚分析流程圖 / PBB/PBDE analytical FLOW CHART

- 1) 測試人員: 翁賜彬 / Name of the person who made measurement: Roman Wong
- 2) 測試負責人: 陳新智 / Name of the person in charge of measurement: Shinjyh Chen 初次測試程序 / First testing process _____

確認程序 / Confirmation process _ . _ ▶



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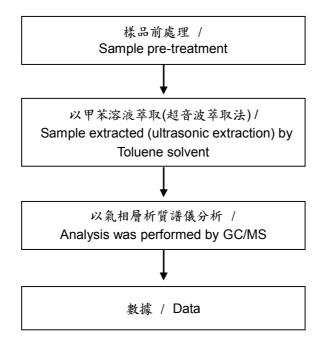
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多苯環芳香族化合物分析流程圖 /

PAHs (Polynuclear Aromatic Hydrocarbons) analytical flow chart

- 1) 測試人員:徐毓明 / Name of the person who made measurement: Andy Shu
- 2) 測試負責人: 陳新智 / Name of the person in charge of measurement: Shinjyh Chen



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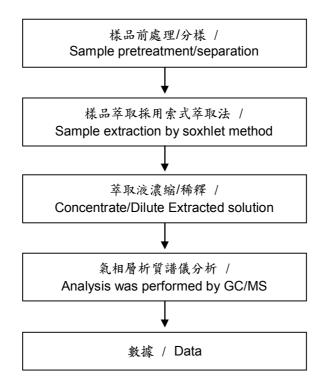
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索式萃取(GC/MS)分析流程圖 /

Analytical flow chart of Soxhlet extraction (GC/MS) procedure

- 1) 測試人員:傅莉雅 / Name of the person who made measurement: Lydia Fu
- 2) 測試負責人: 陳新智 / Name of the person in charge of measurement: Shinjyh Chen
- 測試項目(Test Items): 可塑劑、苯並三唑類化合物、六溴環十二烷 / Phthalate、 Benzotriazole · HBCDD



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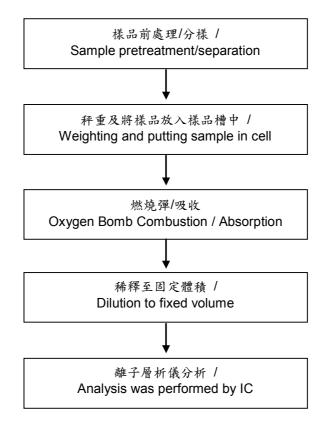
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鹵素分析流程圖 / Analytical flow chart of halogen content

- 1) 測試人員: 陳立倫 / Name of the person who made measurement: Alan Chen
- 2) 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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